TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

TLP2601

Isolated Line Receiver
Simplex / Multiplex Data Transmission
Computer-Peripheral Interface
Microprocessor System Interface
Digital Isolation for A/D, D/A Conversion
Direct Replacement for HCPL-2601

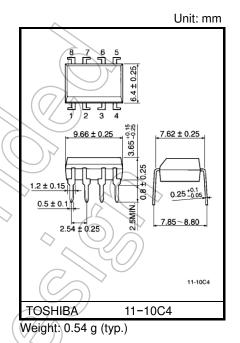
The TOSHIBA TLP2601 a photocoupler which combines a GaAlAs IRed as the emitter and an integrated high gain, high speed photodetector. The output of the detector circuit is an open collector, Schottky clamped transistor.

A Faraday shield integrated on the photodetector chip reduces the effects of capacitive coupling between the input LED emitter and the high gain stages of the detector. This provides an effective common mode transient immunity of $1000V/\mu s$.

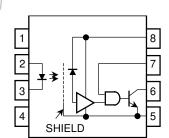
- Input current thresholds: IF = 5mA (max)
- Isolation voltage: 2500Vrms (min)
- Switching speed: 10MBd
- Common mode transient immunity: 1000V/μs (min)
- Guaranteed performance over temp.: 0°C to 70°C
- UL Recognized: UL1577, file No. E67349
- cUL approved :CSA Component Acceptance Service No. 5A, File No.E67349

Truth Table (positive logic)

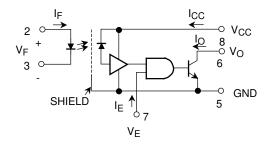
Input	Enable	Output
Н	Н	\\ L
L	Н	Ŧ
Н	☆	Н
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Pin Configuration (top view)



Schematic



A 0.01 to 0.1 μF bypass capacitor must be connected between pins 8 and 5 (see Note 1)

Start of commercial production 1985-01

Recommended Operating Conditions

Characteristic	Symbol	Min	Тур.	Max	Unit
Input current, low level	I _{FL}	0	_	250	μА
Input current, high level	l _{FH}	6.3 (*)	1	20	mA
Supply voltage**, output	Vcc	4.5	_	5.5	٧ <
High level enable voltage	V _{EH}	2.0	_	Vcc	٧
Low level enable voltage	V _{EL}	0	1	0.8	٧
Fan out (TTL load)	N	-	_	8	76
Operating temperature	T _{opr}	0	1	70	°C\

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

(*) 6.3mA is a guard banded value which allows for at least 20% CTR degradation. Initial input current threshold value is 5.0 mA or less.

Absolute Maximum Ratings (no derating required)

		/		
Characteristic		Symbol	Rating	Unit
	Forward current	(F)	20	mA
	Reverse voltage	VR	5	((/y/ s))
LED	Diode power dissipation	PD	100	mW
	Diode power dissipation derating (Ta ≥70°C)	ΔP _D /°C	-1.8	mW/°C
	Junction Temperature	// Tj	125	∕ °C
	Output current	Ю	25	mA
	Output voltage	Vo 〈	-0.5 to 7	٧
tector	Supply voltage (1 minute maximum)	Vcc	7	٧
	Enable input voltage (not to exceed VCC by more than 500mV)	VE	5.5	V
	Output power dissipation	PC	40	mW
	Output Power dissipation derating (Ta ≥ 70°C)	ΔP _C /°C	-0.7	mW / °C
	Junction Temperature	Tj	125	°C
Operating temperature range		Topr	-40 to 85	°C
Storage Temperature range		T _{stg}	−55 to 125	°C
Lead Solder Temperature (10 s)		T _{sol}	260	°C
Isolation voltage		DV ₀	2500	Vrms
(R.H.	≤ 60%, AC 1minute) (Note 10)	BVS	3540	V _{dc}

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

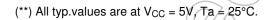
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(**) 1.6mm below seating plane.

^{**}This item denotes operating ranges, not meaning of recommended operating conditions.

Electrical Characteristics (Ta = 0°C to 70°C unless otherwise noted)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
High level output current	ЮН	$V_{CC} = 5.5V, V_O = 5.5V$ $I_F = 250\mu A, V_E = 2.0V$		250	μΑ	
Low level output voltage	V _{OL}	$V_{CC} = 5.5V$, $I_F = 5mA$ $V_E = 2.0V$, $I_{OL}(sinking) = 13mA$	_ <	0.4	0.6	V
High level supply current	Іссн	VCC = 5.5V, IF = 0A, VE = 0.5V	- (7	15	mA
Low level supply current	ICCL	VCC = 5.5V, IF = 10mA, VE = 0.5V	f_{Ω}	12	19	mA
Low level enable current	I _{EL}	V _{CC} = 5.5V, V _E = 0.5V	1/1/))-1.6	-2.0	mA
High level enable current	lEH	V _{CC} = 5.5V, V _E = 2.0V		-1	_	mA
High level enable voltage	V _{EH}	(Note 11)	2.0	-	_	V
Low level enable voltage	VEL	- 4	<u>\</u> _	- </td <td>0.8</td> <td>V</td>	0.8	V
Input forward voltage	VF	I _F = 10mA, Ta = 25°C	> _	1.65	1.75	٧
Input reverse breakdown voltage	BVR	I _R = 10μA, Ta = 25°C	5	7))-	V
Input capacitance	C _{IN}	V _F = 0 V, f = 1MHz	-(C	45	_	pF
Input diode temperature coefficient	ΔVF/ΔΤΑ	IF = 10mA			_	mV / °C
Input-output insulation leakage current	II-O	Relative humidity = 45% Ta=25°C, t = 5 second VI=0 = 3000Vdc, (Note 10)		_	1	μА
Resistance (input-output)	R _I -O	V _{I-O} = 500V, R.H.≤ 60% (Note 10)	5×10 ¹⁰	10 ¹⁴	_	Ω
Capacitance (input-output)	CI-O	f = 1MHz (Note 10)	_	0.6	_	pF

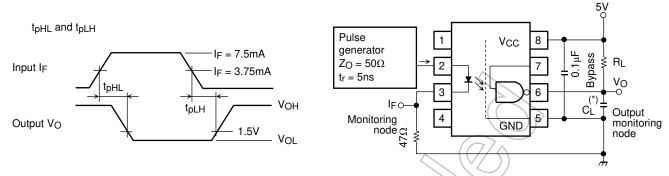




Switching Characteristics (Ta = 25°C, Vcc = 5 V)

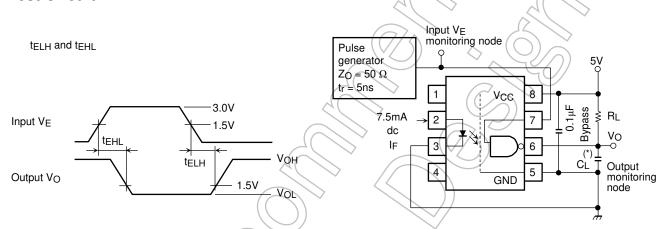
Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit			
Propagation delay time to high output level	t _{pLH}		R _L = 350Ω, C _L = 15pF	_	60	75	ns			
Propagation delay time to low output level	t _{pHL}	1	IF = 7.5mA (Note 2), (Note 3),		60	75	ns			
Output rise time (10-90%)	t _r		(Note 4)&(Note 5)	((-)	30	_	ns			
Output fall time (90-10%)	t _f	1			2 30	_	ns			
Propagation delay time of enable from VEH to VEL	tELH	_	$R_L = 350\Omega$, $C_L = 15pF$ $I_F = 7.5mA$	9	25	_	ns			
Propagation delay time of enable from V _{EL} to V _{EH}	tehL teh	2	2	2	2	VEH = 3.0V VEL = 0.5V (Note 6) & (Note 7)	_	25	_	ns
Common mode transient immunity at high output level	СМн	2	$V_{CM} = 400V$ $R_L = 350\Omega$ $V_{O(min)} = 2V$ $I_F = 0mA$, (Note 9)	1000	10000	> -	V/µs			
Common mode transient immunity at low output level	CML	3	$V_{CM} = 400V \\ R_{L} = 350\Omega \\ V_{O(max)} = 0.8V \\ I_{F} = 7.5 mA, \qquad (Note 8)$	-1000	-10000	_	V/µs			

Test Circuit 1.



(*) CL is approximately 15pF which includes probe and stray wiring capacitance.

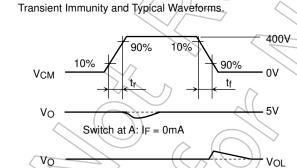




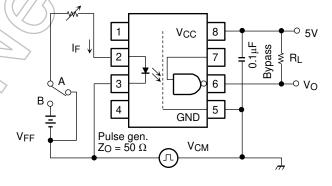
(*) C_L is approximately 15pF which includes probe and stray wiring capacitance.

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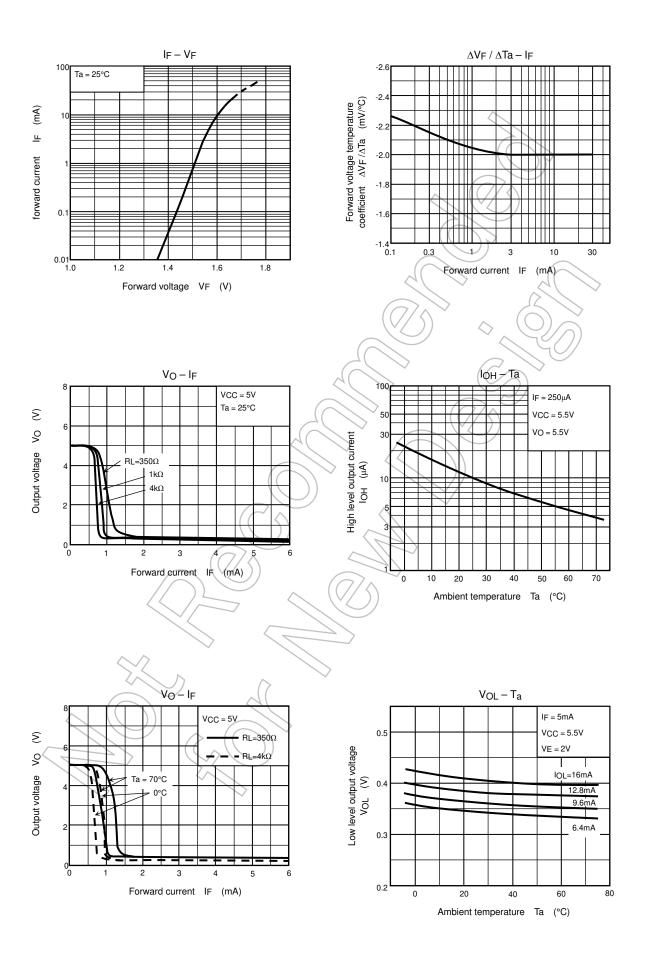
Test Circuit 3.

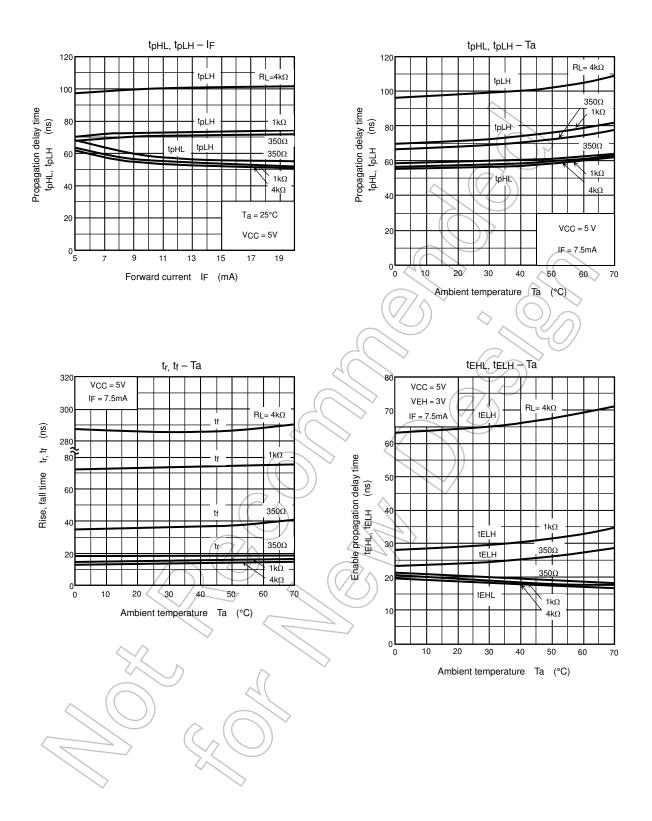


Switch at B: IF = 5mA



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Notes

- 1. The V_{CC} supply voltage to each TLP2601 isolator must be bypassed by a $0.1\mu F$ capacitor of larger. This can be either a ceramic or solid tantalum capacitor with good high frequency characteristic and should be connected as close as possible to the package V_{CC} and GND pins of each device.
- 2. t_{pHL} Propagation delay is measured from the 3.75mA level on the low to high transition of the input current pulse to the 1.5V level on the high to low transition of the output voltage pulse.
- 3. t_{pLH} · Propagation delay is measured from the 3.75mA level on the high to low transition of the input current pulse to the 1.5V level on the low to high transition of the output voltage pulse.
- 4. tf · Fall time is measured from the 10% to 90% levels of the high to low transition on the output pulse.
- 5. t_r · Rise time is measured from the 90% to 10% levels of the low to high transition on the output pulse.
- 6. tehl Enable input propagation delay is measured from the 1.5V level on the low to high transition of the input voltage pulse to the 1.5V level on the high to low transition of the output voltage pulse.
- 7. telh Enable input propagation delay is measured from the 1.5V level on the high to low transition of the input voltage pulse to the 1.5V level on the low to high transition of the output voltage pulse.
- 8. CML The maximum tolerable rate of fall of the common mode voltage to ensure the output will remain in the low output state (i.e. $V_{OUT} < 0.8V$).

 Measured in volts per microsecond (V / μ s).
- 9. CMH The maximum tolerable rate of fall of the common mode voltage to ensure the output will remain in the high state (i.e. $V_{OUT} > 2.0V$).

 Measured in volts per microsecond (V / μ s).

Volts/microsecond can be translated to sinusoidal voltages:

 $V/\mu s = \frac{(VCM)}{dt} = f_{CM} V_{CM} (p.p.)$

Example:

 $V_{CM} = 318V_{pp}$ when $f_{CM} = 1$ MHz using CML and CMH = 1000V / μs data sheet specified minimum.

- 10. Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together, and Pins 5, 6, 7 and 8 shorted together.
- 11. Enable · No pull up resistor required as the device has an internal pull up resistor. input

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